	arcn Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/634,758	NAKAGAWA, YUJI	
Examiner	Art Unit	
Than Nguyen	2187	

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	oclass Date Exami	
711	151,158	10/4/2006	NTV
711	167	10/4/2006	NTV

SEARCH NOT (INCLUDING SEARCH	STRATEGY)
	DATE	EXMR
West IEEE Inventor	10/4/2006	NTV